

## 1. Description

BLP04N08, the N-channel Enhanced Power MOSFETs, is obtained by advanced double trench technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. This is suitable device for BMS and high current switching applications.

### KEY CHARACTERISTICS

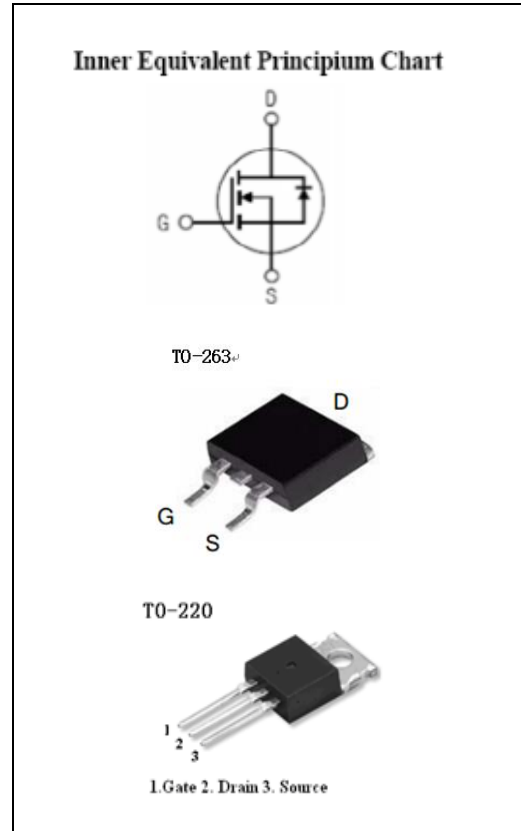
Parameter	Value	Unit
V <sub>DSS</sub>	85	V
I <sub>D</sub>	120	A
R <sub>DS(on).typ</sub>	3	mΩ

### FEATURES

- Fast Switching
- Low On-Resistance (  $R_{DS(on)} \leq 3.6m\Omega$  )
- Low Gate Charge
- Low Reverse transfer capacitances
- High avalanche ruggedness
- RoHS product

### APPLICATIONS

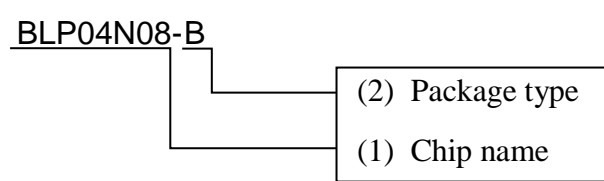
- BMS
- Motor drivers



## ORDERING INFORMATION

Ordering Codes	Package	Product Code	Packing
BLP04N08-B	TO-263	P04N08	Reel
BLP04N08-P	TO-220	P04N08	Tube

**BLP04N08-B**



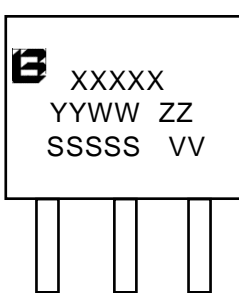
(2) Package type

(1) Chip name

(1) BLP04N08: 4mΩ/85V

(2) B: TO-263

    P: TO-220



XXXXX: Product Code

YYWW: Year&Week

ZZ: Assembly Code

SSSSS: Lot Code

VV: Classification

## 2. ABSOLUTE RATINGS

at  $T_C=25^\circ\text{C}$ , unless otherwise specified

Symbol	Parameter	Rating	Units
$V_{DSS}$	Drain-Source Voltage	85	V
$I_D$	Continuous Drain Current, Silicon Limited	185	A
	Continuous Drain Current, Package Limited	120	A
	Continuous Drain Current @ $T_C=100^\circ\text{C}$ , Silicon Limited	117.2	A
$I_{DM}$ <sup>Note1</sup>	Pulsed Drain Current	480	A
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$E_{AS}$ <sup>Note2</sup>	Avalanche Energy	289	mJ
$P_D$	Power Dissipation	208.3	W
	Derating Factor above $25^\circ\text{C}$	1.67	W/ $^\circ\text{C}$
$T_J, T_{stg}$	Operating Junction and Storage Temperature Range	150, $-55$ to $150$	$^\circ\text{C}$
$T_L$	Maximum Temperature for Soldering	260	$^\circ\text{C}$

Note1: Repetitive Rating: Pulse width limited by maximum junction temperature

Note2:  $L=0.5\text{mH}$ ,  $I_{as}=34\text{A}$ , Start  $T_J=25^\circ\text{C}$

## 3. Thermal characteristics

Symbol	Parameter	Max	Units
$R_{\theta JC}$	thermal resistance, Junction-Case	0.6	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	thermal resistance, Junction-Ambient	62.5	$^\circ\text{C}/\text{W}$

## 4. Electrical Characteristics

at  $T_C=25^\circ\text{C}$ , unless otherwise specified

OFF Characteristics						
Symbol	Parameter	Test Conditions	Values			Units
			Min	Typ	Max	
$V_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$ , $I_D=250\mu\text{A}$	85	95	--	V
$I_{DSS}$	Drain-Source Leakage Current	$V_{DS}=85\text{V}$ , $V_{GS}=0\text{V}$	--	--	1	$\mu\text{A}$
		$V_{DS}=68\text{V}$ , $V_{GS}=0\text{V}$ @ $T_C=125^\circ\text{C}$	--	--	100	$\mu\text{A}$
$I_{GSS(F)}$	Gate-Source Forward Leakage	$V_{GS}=+20\text{V}$	--	--	100	nA
$I_{GSS(R)}$	Gate-Source Reverse Leakage	$V_{GS}=-20\text{V}$	--	--	-100	nA

**ON Characteristics**

Symbol	Parameter	Test Conditions	Values			Unit S
			Min	Typ	Max	
$R_{DS(on)}$	Drain-Source On-Resistance	$V_{GS}=10V, I_D=50A$	--	3	3.6	m $\Omega$
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	2	3	4	V

Pulse width  $t_p \leq 300\mu s, \delta \leq 2\%$

**Dynamic Characteristics**

Symbol	Parameter	Test Conditions	Values			Units
			Min	Typ	Max	
$C_{iss}$	Input Capacitance	$V_{DS}=42.5V,$ $V_{GS}=0,$ $f=1MHz$	--	6234	--	pF
$C_{oss}$	Output Capacitance		--	1181	--	
$C_{rss}$	Reverse Transfer Capacitance		--	97	--	
$Q_g$	Total Gate Charge	$V_{DD}=42.5V,$ $I_D=50A,$ $V_{GS}=10V$	--	124	--	nC
$Q_{gs}$	Gate-Source charge		--	31.2	--	
$Q_{gd}$	Gate-Drain charge		--	39.2	--	
$R_G$	Gate resistance	$V_{GS}=0, V_{DS}=0$		1.75		$\Omega$

**Switching Characteristics**

Symbol	Parameter	Test Conditions	Values			Units
			Min	Typ	Max	
$t_{d(on)}$	Turn-On Delay Time	$V_{DD}=42.5V,$ $I_D=10A,$ $V_{GS}=10V,$ $R_G=3\Omega,$ Resistive Load	--	41	--	ns
$t_r$	Rise Time		--	68	--	
$t_{d(off)}$	Turn-Off Delay Time		--	76	--	
$t_f$	Fall Time		--	44	--	

**Source-Drain Diode Characteristics**

Symbol	Parameter	Test Conditions	Values			Units
			Min	Typ	Max	
$I_S$	Continuous Source Current		--	--	120	A
$I_{SM}$	Maximum Pulsed Current		--	--	480	A
$V_{SD}$	Diode Forward Voltage	$V_{GS}=0V, I_S=50A$	--	--	1.2	V
$T_{rr}$	Reverse Recovery Time	$I_S=30A, V_{GS}=0,$ $di/dt=100A/us$	--	80	--	ns
$Q_{rr}$	Reverse Recovery Charge		--	112	--	nC

## 5. Characteristics Curves

Figure 1. Safe Operating Area

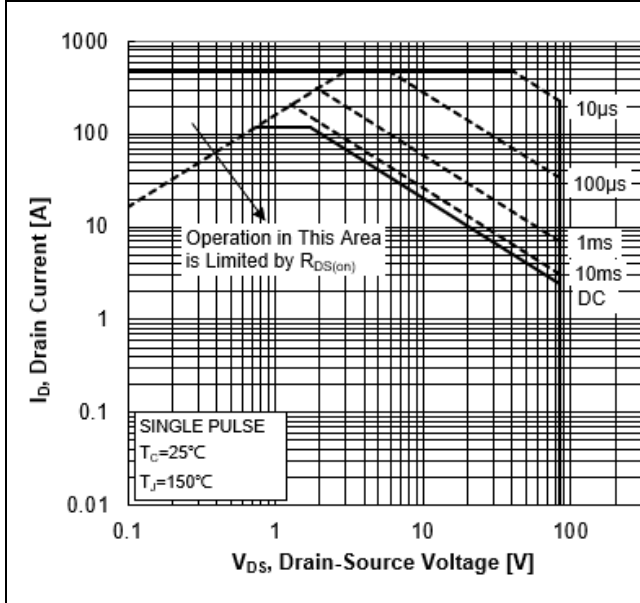


Figure 2. Maximum Power Dissipation vs Case Temperature

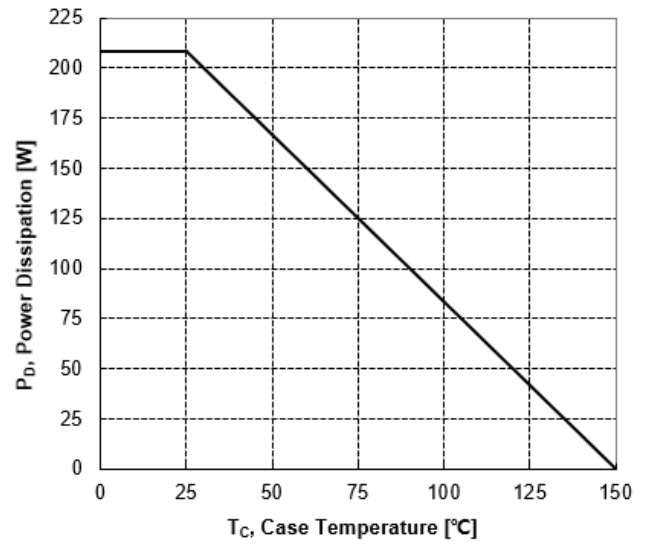


Figure 3. Maximum Continuous Drain Current vs Case Temperature

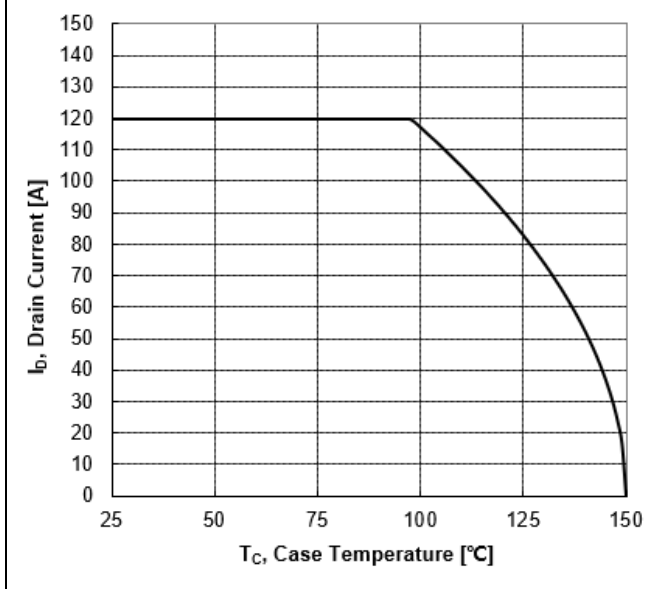
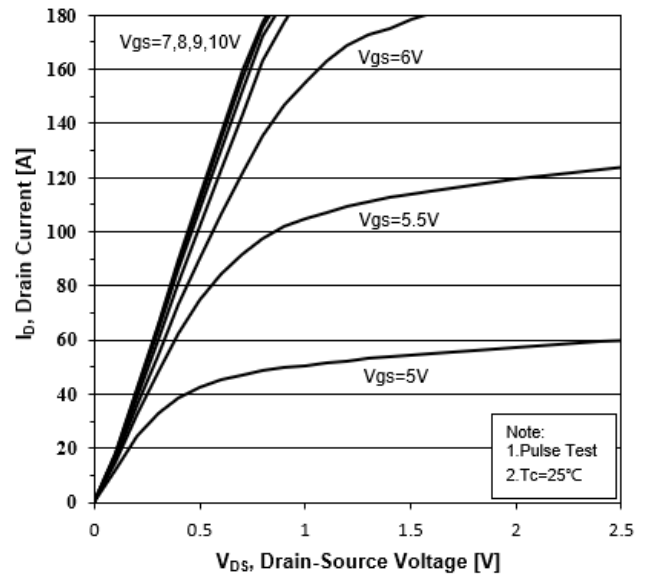
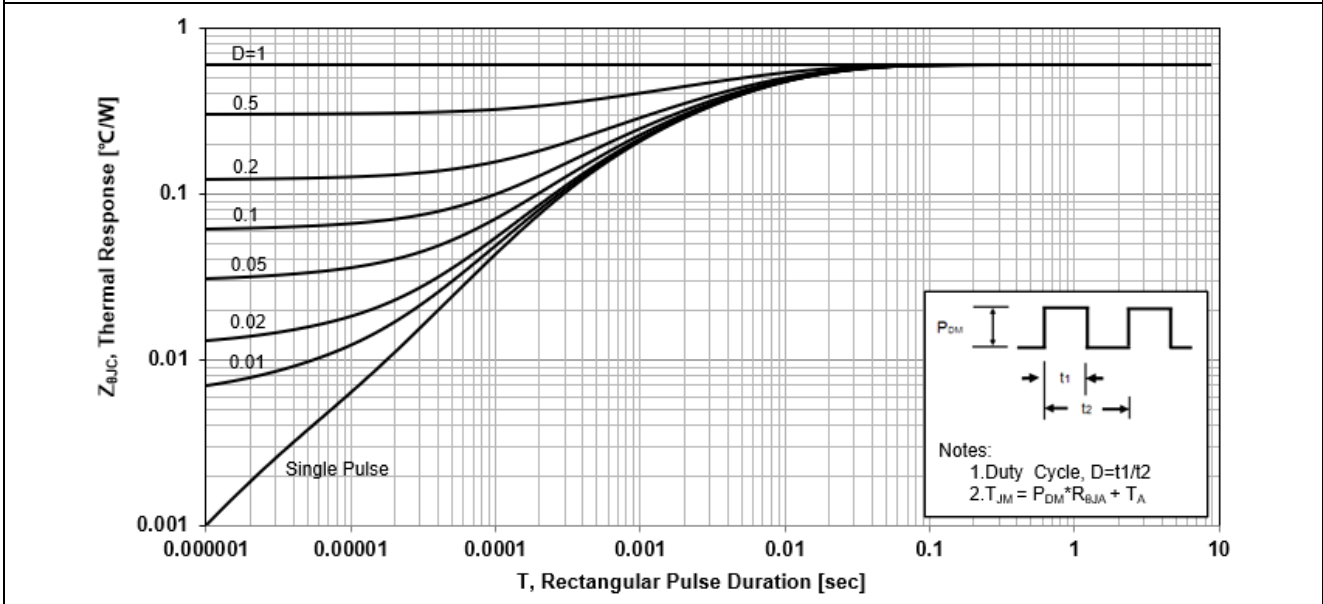


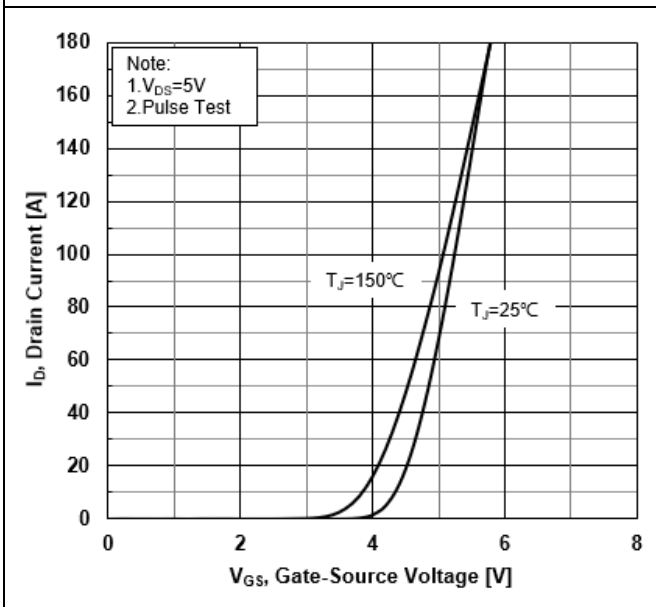
Figure 4. Typical Output Characteristics



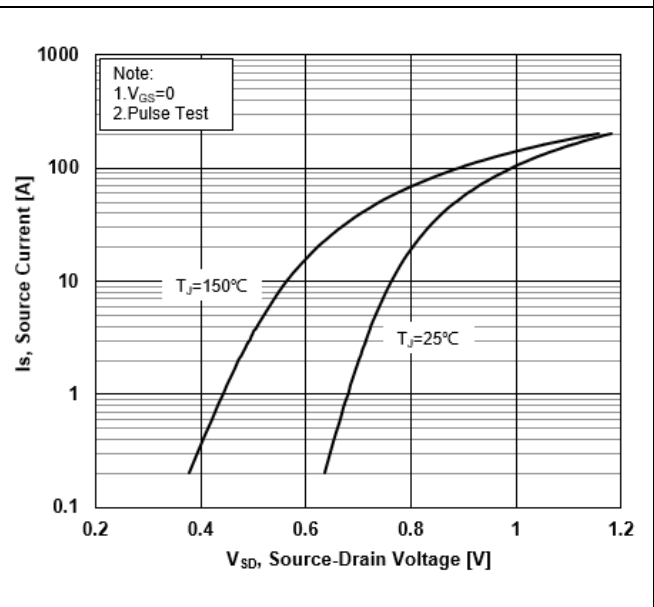
**Figure 5. Transient Thermal Impedance**



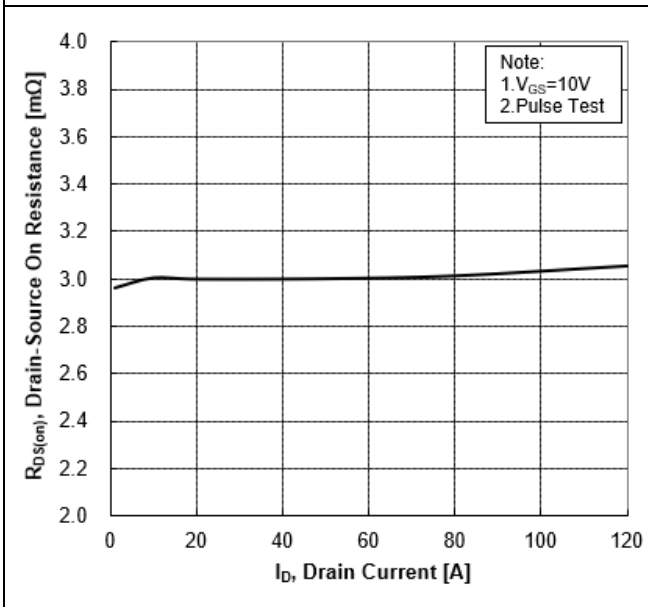
**Figure 6. Typical Transfer Characteristics**



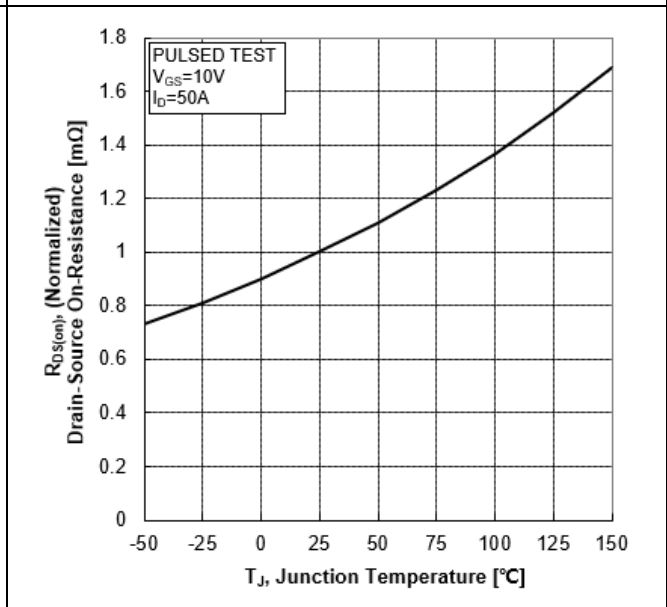
**Figure 7. Source-Drain Diode Forward Characteristics**



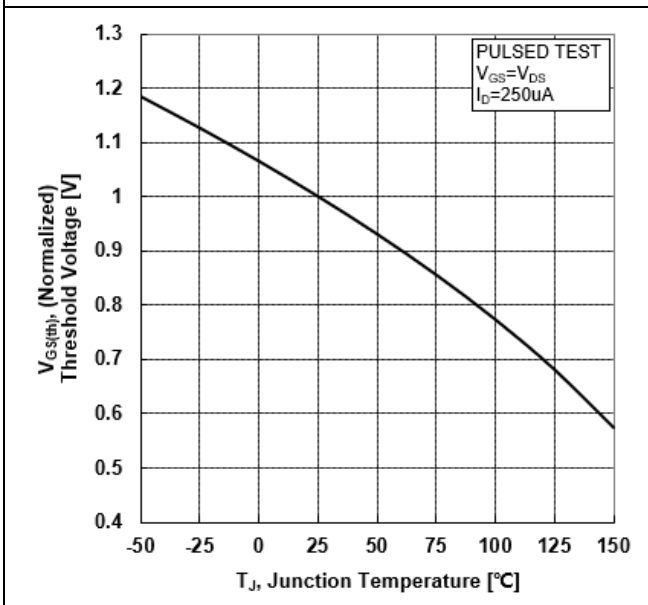
**Figure 8. Drain-Source On-Resistance vs Drain Current**



**Figure 9. Normalized On-Resistance vs Junction Temperature**



**Figure 10. Normalized Threshold Voltage vs Junction Temperature**



**Figure 11. Normalized Breakdown Voltage vs Junction Temperature**

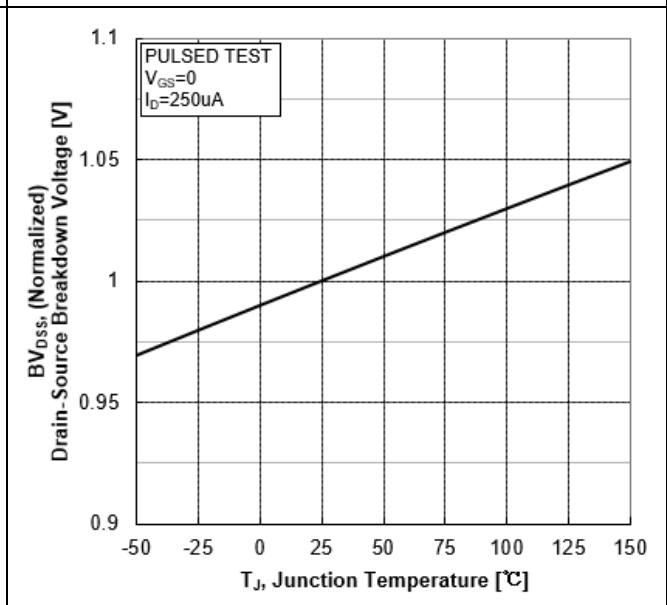


Figure 12. Capacitance Characteristics

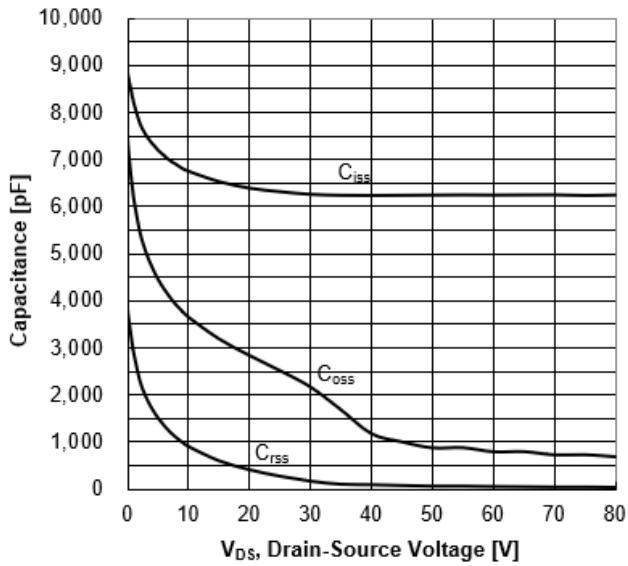
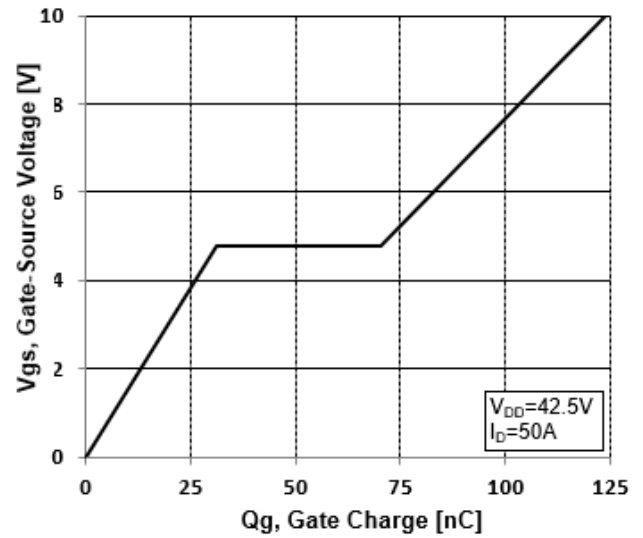


Figure 13. Typical Gate Charge vs Gate-Source Voltage



## 6. Test Circuit and Waveform

Figure 14. Resistive Switching Test Circuit

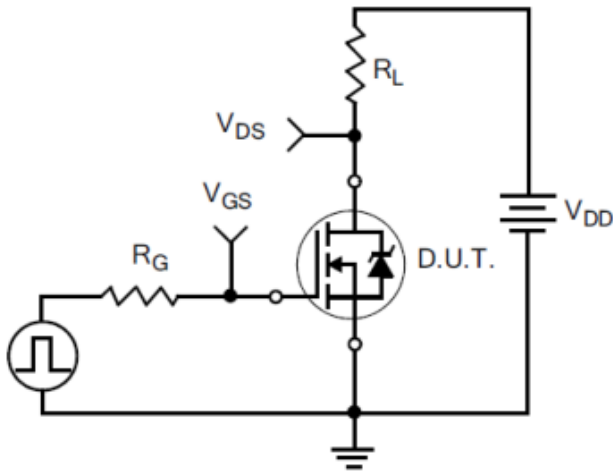


Figure 15. Resistive Switching Waveforms



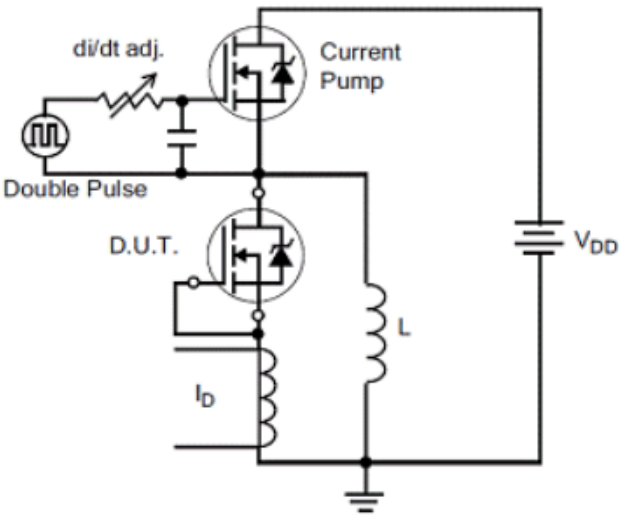
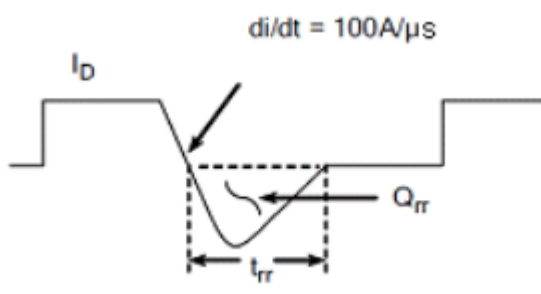
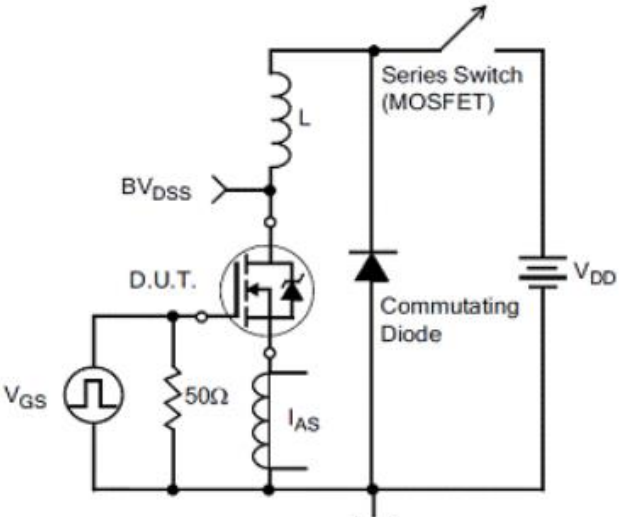
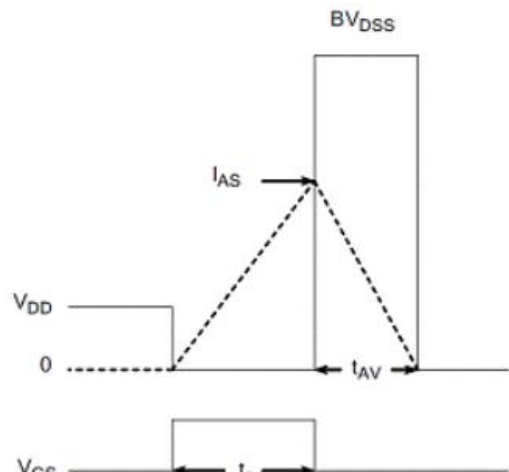
Figure 16. Gate Charge Test Circuit



Figure 17. Gate Charge Waveforms

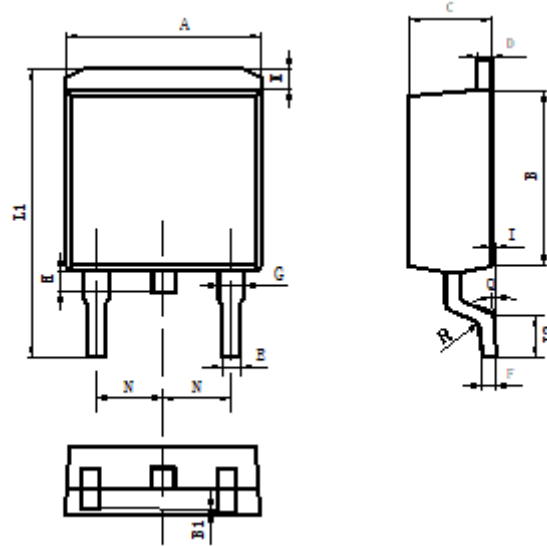




<p><b>Figure 18. Diode Reverse Recovery Test Circuit</b></p> 	<p><b>Figure 19. Diode Reverse Recovery Waveform</b></p> 
<p><b>Figure 20. Unclamped Inductive Switching Test Circuit</b></p> 	<p><b>Figure 21. Unclamped Inductive Switching Waveform</b></p>  $E_{AS} = \frac{I_{AS}^2 L}{2}$

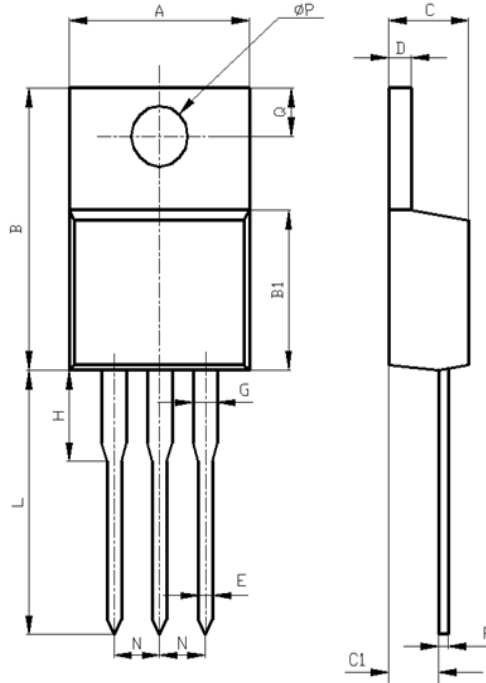
## 7. Package Description

### TO-263



Items	Values(mm)	
	MIN	MAX
A	9.80	10.40
B	8.90	9.50
B1	0	0.10
C	4.40	4.80
D	1.16	1.37
E	0.70	0.95
F	0.30	0.60
G	1.07	1.47
H	1.30	1.80
K	0.95	1.37
L1	14.50	16.50
L2	1.60	2.30
I	0	0.2
Q	0°	8°
R	0.4	0.4
N	2.39	2.69

TO-220



Items	Values(mm)	
	MIN	MAX
A	9.60	10.6
B	15.0	16.0
B1	8.90	9.50
C	4.30	4.80
C1	2.30	3.10
D	1.20	1.40
E	0.70	0.90
F	0.30	0.60
G	1.17	1.37
H	2.70	3.80
L	12.6	14.8
N	2.34	2.74
Q	2.40	3.00
ΦP	3.50	3.90

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